

# N-Channel 100 V (D-S) MOSFET

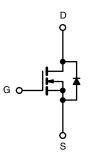
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	100				
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 V$	0.005				
I <sub>D</sub> (A) <sup>a</sup>	120				
Configuration	Single				

### **FEATURES**

- ThunderFET<sup>®</sup> power MOSFET
- Maximum 175 °C junction temperature
- 100 % R<sub>g</sub> and UIS tested
- Material categorization: for definitions of compliance please see







N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)					
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V <sub>DS</sub>	100	v		
Gate-Source Voltage	V <sub>GS</sub>	± 20	v		
Continuous Drain Current (T 150 °C)	$T_C = 25 \ ^{\circ}C$		120 <sup>d</sup>	А	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>C</sub> = 70 °C	I <sub>D</sub>	90 d		
Pulsed Drain Current (t = 100 µs)	I <sub>DM</sub>	480	A		
Avalanche Current		I <sub>AS</sub>			73
Single Avalanche Energy <sup>a</sup>	L = 0.1 mH	E <sub>AS</sub>	266	mJ	
Maximum Power Dissipation <sup>a</sup>	T <sub>C</sub> = 25 °C	- P <sub>D</sub> -	370 <sup>b</sup>	W	
	T <sub>C</sub> = 125 °C	r D	120 <sup>b</sup>	vv	
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C	

THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	LIMIT	UNIT		
Junction-to-Ambient (PCB Mount) <sup>c</sup>	R <sub>thJA</sub>	40	°C/W		
Junction-to-Case (Drain)	R <sub>thJC</sub>	0.4			

Notes

- a. Duty cycle  $\leq$  1 %.
- b. See SOA curve for voltage derating.
- c. When mounted on 1" square PCB (FR4 material).
- d. Package limited.

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static				1			
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS}$ = 0 V, $I_D$ = 250 $\mu$ A	100	-	-	V	
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	2.5	-	4	v	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$	-	-	± 250	nA	
		V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V	-	-	1	- μΑ	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 ^{\circ}\text{C}$	-	-	150		
		$V_{DS}$ = 100 V, $V_{GS}$ = 0 V, $T_{J}$ = 175 °C	-	-	5	mA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \geq 10 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	120	-	-	А	
	_	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 20 A	-	0.005	-	Ω	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS}$ = 7.5 V, $I_D$ = 15 A	-	0.006	-		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 20 A	-	82	-	S	
Dynamic <sup>b</sup>				1			
Input Capacitance	Ciss		-	10000	-	pF	
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 V, V_{DS} = 50 V, f = 1 MHz$	-	2025	-		
Reverse Transfer Capacitance	C <sub>rss</sub>		-	165	-		
Total Gate Charge <sup>c</sup>	Qg		-	76	120		
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$	-	23	-	nC	
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>		-	17	-		
Gate Resistance	Rg	f = 1 MHz	0.6	3.3	6.6	Ω	
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>		-	15	30	ns	
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DD}$ = 50 V, R <sub>L</sub> = 5 $\Omega$	-	22	40		
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	$I_D \cong 10$ Å, $V_{GEN} = 10$ V, $R_g = 1$ $\Omega$	-	55	100		
Fall Time <sup>c</sup>	t <sub>f</sub>		-	15	30		
Drain-Source Body Diode Ratings ar	nd Characteri	stics <sup>b</sup> (T <sub>C</sub> = 25 °C)		1			
Pulsed Current	I <sub>SM</sub>		-	-	480	А	
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	$I_{\rm F} = 10 \text{ A}, V_{\rm GS} = 0 \text{ V}$	-	0.8	1.5	V	

Notes

a. Pulse test; pulse width  $\leq 300~\mu\text{s},~\text{duty}~\text{cycle} \leq 2~\%.$ 

b. Guaranteed by design, not subject to production testing.

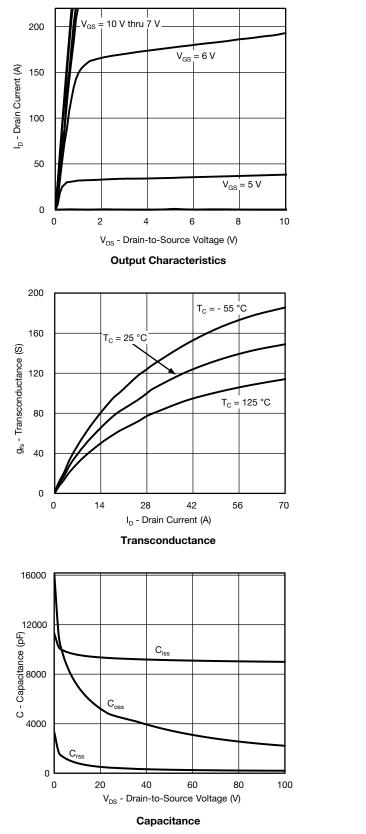
c. Independent of operating temperature.

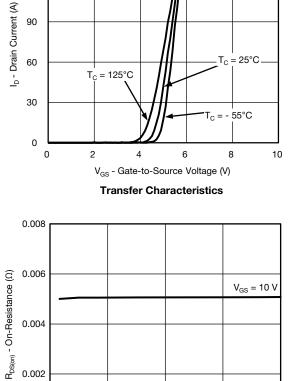
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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# **TYPICAL CHARACTERISTICS** ( $T_A = 25 \text{ °C}$ , unless otherwise noted)

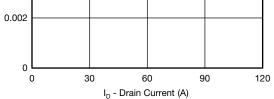


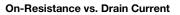


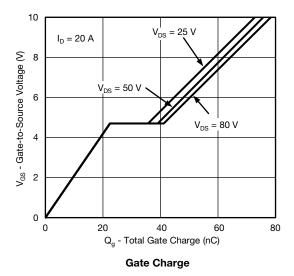
150

120

90

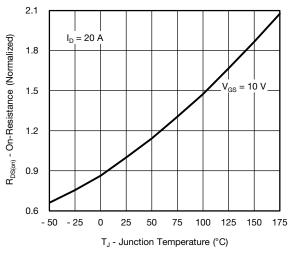




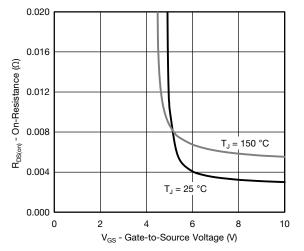




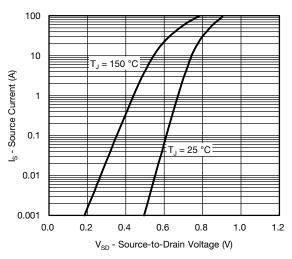
# **TYPICAL CHARACTERISTICS** ( $T_A = 25 \text{ °C}$ , unless otherwise noted)



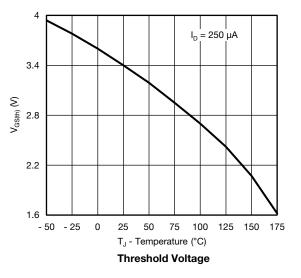


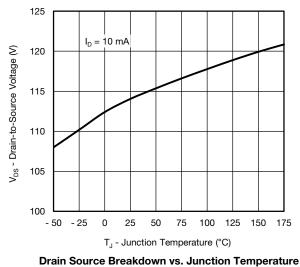


On-Resistance vs. Gate-to-Source Voltage



Source Drain Diode Forward Voltage

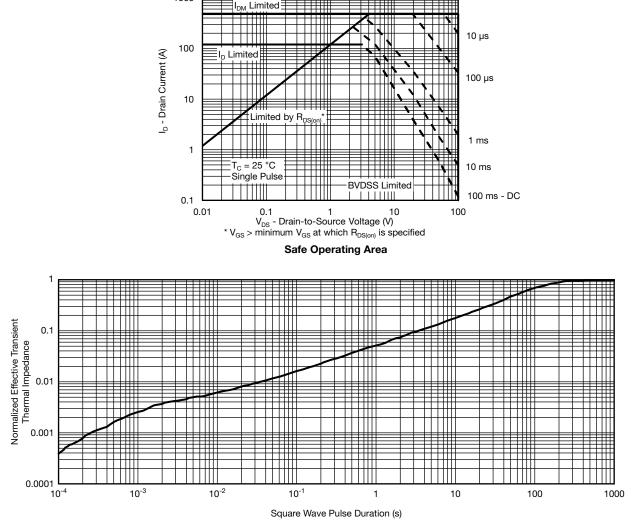






## **THERMAL RATINGS** ( $T_A = 25 \text{ °C}$ , unless otherwise noted)

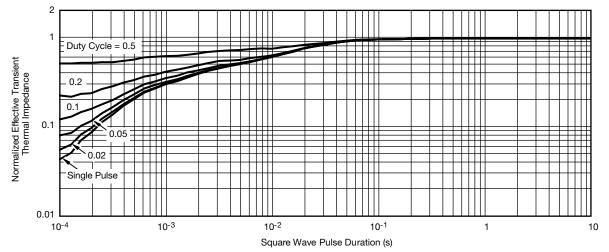
1000



Normalized Thermal Transient Impedance, Junction-to-Ambient



## **THERMAL RATINGS** ( $T_A = 25 \text{ °C}$ , unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Case

#### Note

• The characteristics shown in the two graphs

- Normalized Transient Thermal Impedance Junction to Ambient (25 °C)

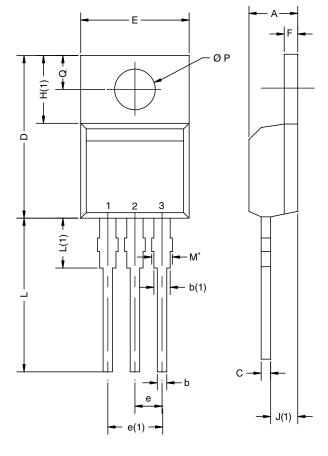
- Normalized Transient Thermal Impedance Junction to Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.

# IPP100N10S3-05



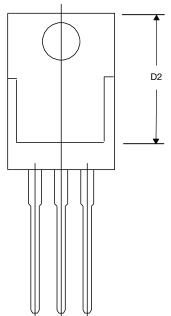
# **TO-220AB**



	MILLIN	MILLIMETERS INCHES		HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
D2	12.19	12.70	0.480	0.500	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: T14-0413-Rev. P, 16-Jun-14 DWG: 5471					

## Note

\* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM





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